

■ Electrical Characteristics $T_a = 25^\circ\text{C} \pm 3^\circ\text{C}$

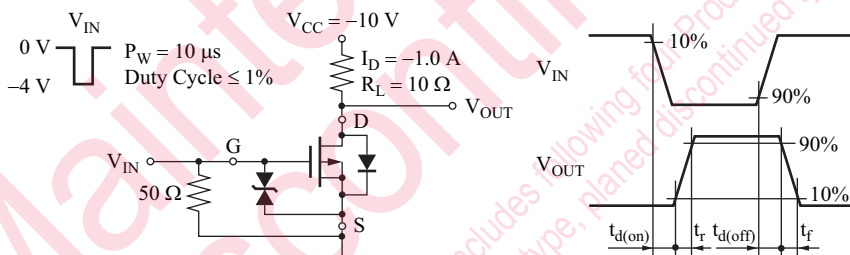
• FET

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Drain-source surrender voltage	V_{DSS}	$I_D = -1.0 \text{ mA}, V_{GS} = 0$	-20			V
Drain-source cutoff current	I_{DSS}	$V_{DS} = -20 \text{ V}, V_{GS} = 0$			-1.0	μA
Gate-source cutoff current	I_{GSS}	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0$			± 10	μA
Gate threshold voltage	V_{TH}	$I_D = -1.0 \text{ mA}, V_{DS} = -10 \text{ V}$	-0.4	-0.75	-1.1	V
Drain-source ON resistance 1 *1	$R_{DS(on)1}$	$I_D = -1.0 \text{ A}, V_{GS} = -4.0 \text{ V}$		80	120	$\text{m}\Omega$
Drain-source ON resistance 2 *1	$R_{DS(on)2}$	$I_D = -1.0 \text{ A}, V_{GS} = -2.5 \text{ V}$		100	170	$\text{m}\Omega$
Drain-source ON resistance 3 *1	$R_{DS(on)3}$	$I_D = -0.5 \text{ A}, V_{GS} = -1.8 \text{ V}$		140	230	$\text{m}\Omega$
Forward transfer admittance *1	$ Y_{fs} $	$I_D = -1.0 \text{ A}, V_{DS} = -10 \text{ V}, f = 1 \text{ kHz}$	3.0			S
Short-circuit input capacitance (Common source)	C_{iss}			300		pF
Short-circuit output capacitance (Common source)	C_{oss}	$V_{DS} = -10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		30		pF
Reverse transfer capacitance (Common source)	C_{rss}			35		pF
Turn-on delay time *2	$t_{d(on)}$	$V_{DD} = -10 \text{ V}, V_{GS} = 0 \text{ V to } -4 \text{ V},$ $I_D = -1.0 \text{ A}$		6		ns
Rise time *2	t_r			8		ns
Turn-off delay time *2	$t_{d(off)}$	$V_{DD} = -10 \text{ V}, V_{GS} = -4 \text{ V to } 0 \text{ V},$ $I_D = -1.0 \text{ A}$		57		ns
Fall time *2	t_f			55		ns

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. *1: Pulse measurement

*2: Measurement circuit

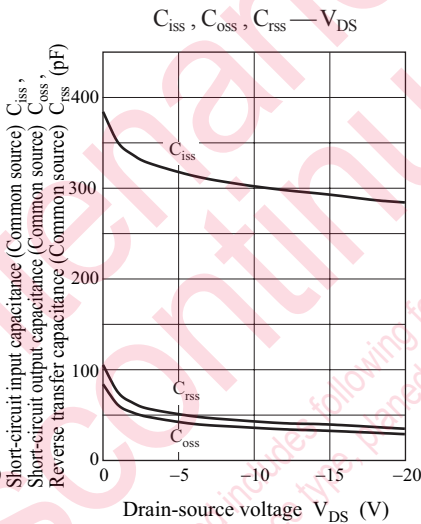
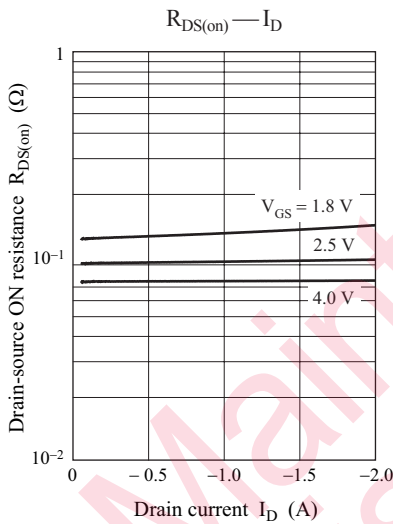
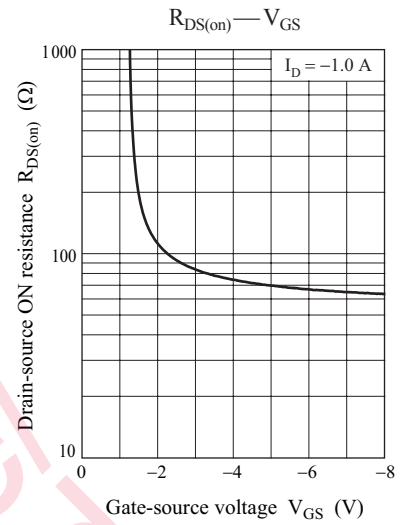
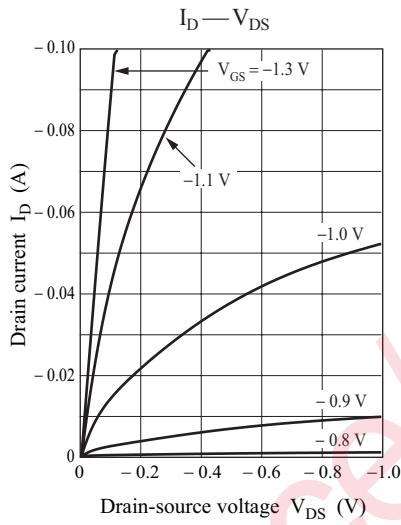
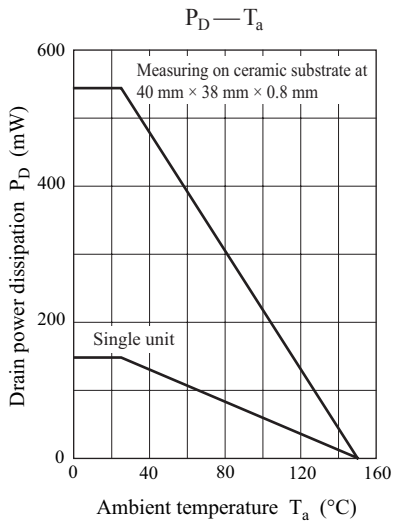


• SBD

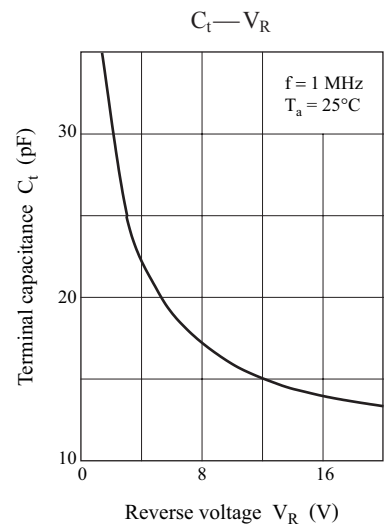
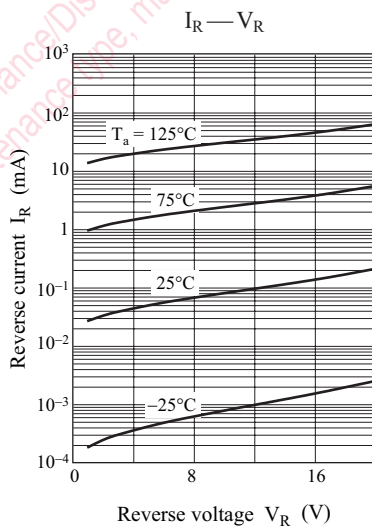
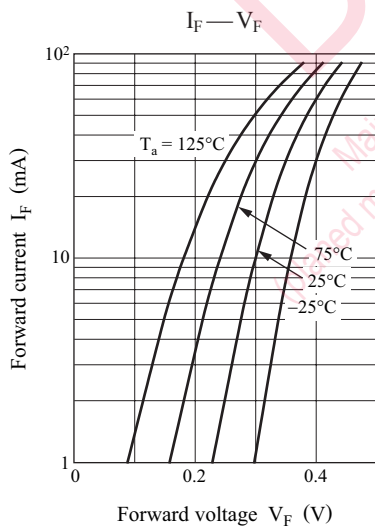
Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Forward voltage	V_F	$I_F = 800 \text{ mA}$			0.47	V
Reverse current	I_R	$V_R = 20 \text{ V}$			80	μA

Note: Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 measuring methods for diodes.

Characteristics charts of FET

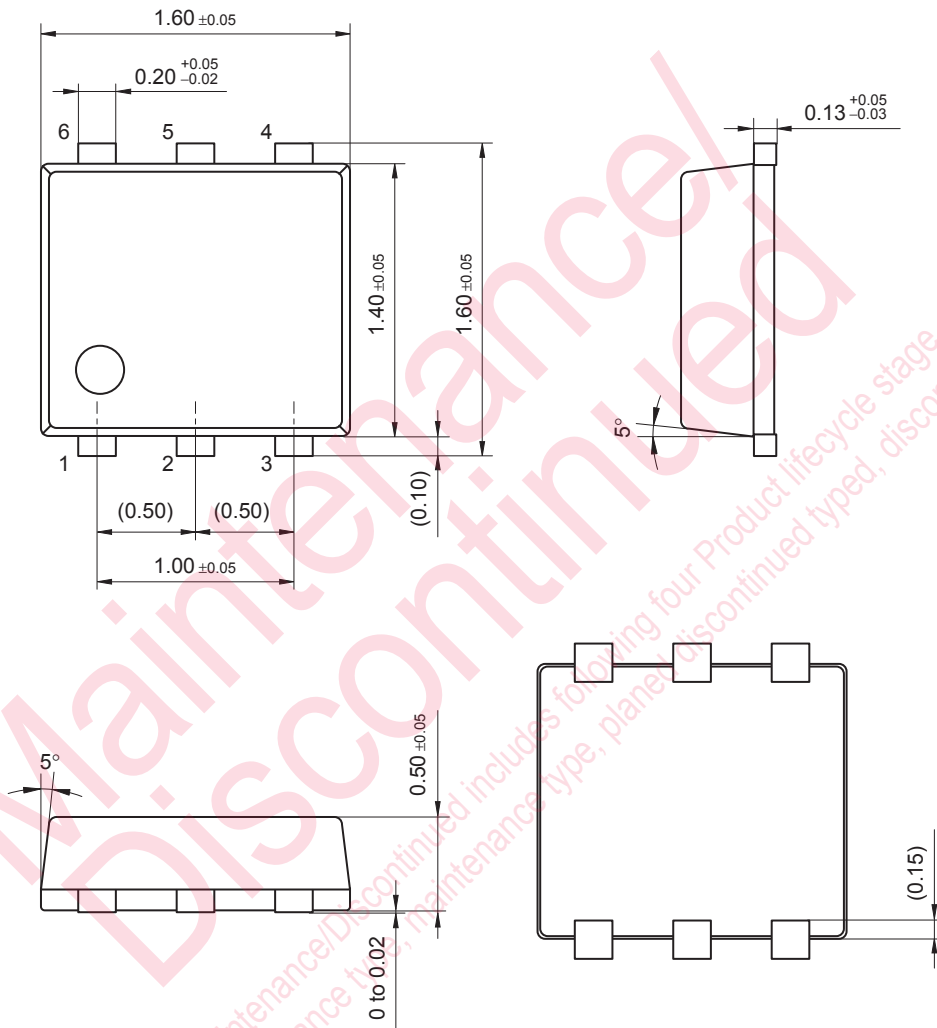


Characteristics charts of SBD



WSSMini6-F1

Unit: mm



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